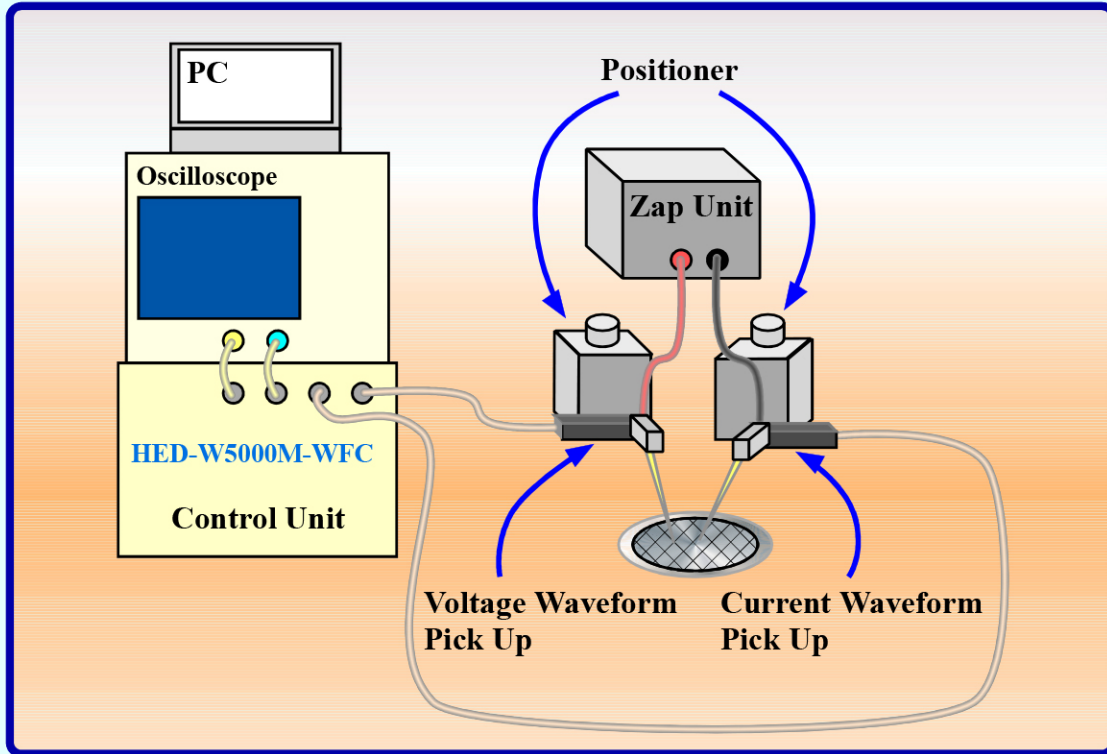




ESD Tester : HED-W5000M-WFC

Capture waveform in real time

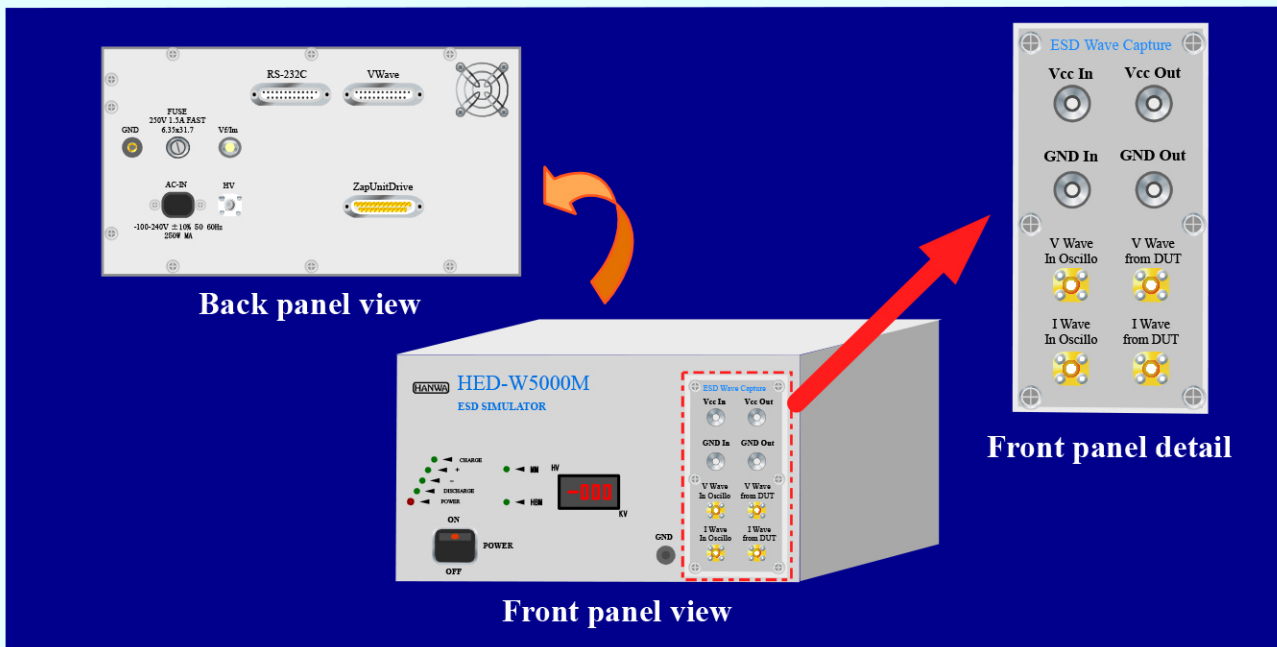
Complies with IEC 61000-4-2



Features

US Patent pending

1. HBM waveform is captured in real time at the wafer level.
2. HBM/MM zapping, in conformity with JEDEC, ESDA and JEITA Standards.
3. Enhanced efficiency: perform two tests with a single tester.
4. Zap units can be installed on a probe station.
5. Package level performance can be extrapolated from wafer level test results.
6. Optional HMM zap test (IEC 61000-4-2).
7. ESD guns and ground-planes for IEC61000-4-2 testing are no longer needed.

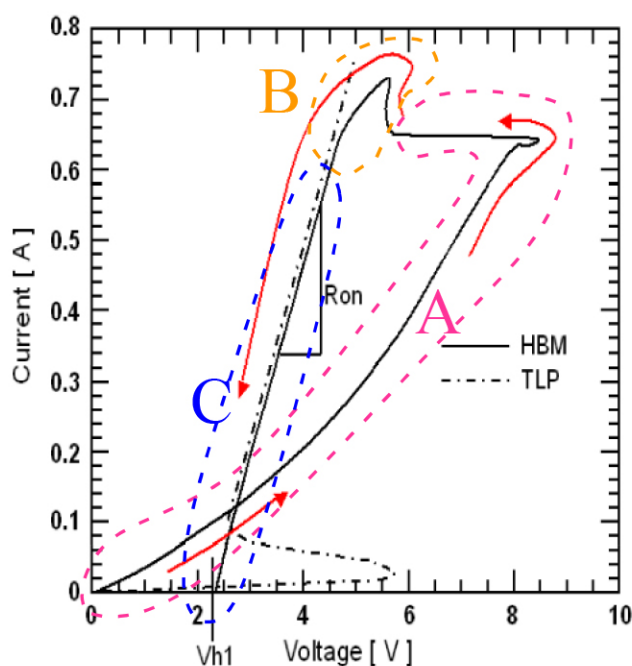
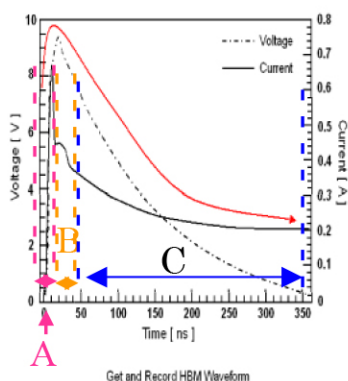
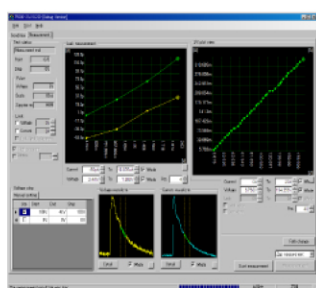


Back panel view

Front panel view

Front panel detail

Sample Output, Comparing TLP and HBM curves



HBM Waveform analysis (Compare TLP and HBM IV Curves)

Specifications

Model	HED-W5000M-WFC		
Waveform	HBM	JEDEC, ESDA, JEITA	
	MM	JEDEC, ESDA, JEITA	
	HMM	IEC 61000-4-2	
Charging voltage	0 ~ +/-4kV (8kV option)		
Charging resolution	5V		
Charging accuracy	1 % +/-5V		
ZAP count	1 ~ 9		
Interval time	0.8 ~ 9.9 s		
Test pins	Manual positioning		
X-Y-Z range of mobility	Depends on user's manipulator		
Physical (main unit)	330(W) / 520(D) / 200(H)	15 Kg	(PC no contained)
Physical (Zap unit)	75(W) / 120(D) / 105(H)	1 Kg	
Curve Tracing voltage & step & Resolution	0 ~ +/- 40V	0.1V step	0.1V Resolution
Curve Tracing current	Max 100mA		
Detection resistance	10,100,1k,10k,100k,1M ohm		
Measurement range	10nA,100nA,1uA,10uA,100uA,1mA,10mA,100mA		
Curve Tracing Accuracy	1% +/- (1/500 F.S +/- 10nA)		
Measurement point	max 20 point		
Variable quantity	Percentage change, Absolute Value		
Main unit control	RS-232C		
Oscilloscope model	Tektronix TDS3052B		
Oscilloscope control	GPIB		
Operation	Windows		

美浜国际贸易（上海）有限公司

电话: (021) 5407-2091

手机: 1356-4666-529

地址: 上海市徐汇区宜山路425号 (光启城2213室)

● Agency